Space Environmental Effects Knowledgebase

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Materials and Processes Laboratory
managed at the Marshall Space Flight Center

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National Aeronautics and
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# TABLE OF CONTENTS

I. Introduction .......................................................................................................................... 1

II. Structure of the Satellite Contamination and Materials Outgassing Knowledgebase ........ 3  
    A) Material Outgassing Data ............................................................................................. 3  
    B) Round-Robin Material Outgassing Tests .................................................................... 5  
    C) Flight QCM Data ......................................................................................................... 6  
    D) MSX Satellite Program ............................................................................................... 7  
    E) Optical Properties of Contaminant Films at Cryogenic Temperatures ....................... 9

III. To obtain your copy of the Space Environment Effects Knowledgebase ....................... 12

IV. Summary ............................................................................................................................ 13

V. Acknowledgements ............................................................................................................. 15

References ................................................................................................................................ 16

Appendix 1 .................................................................................................................................. 29

Appendix 2. Refractive and Absorptive Indices listing for thin solid films condensed  
from gases and material outgassing products ........................................................................ 36

Appendix 3. Software Usage Agreement Application for gaining access to NASA Space  
Environment Effects Knowledgebase .................................................................................... 39
LIST OF FIGURES

1. Typical ASTM E-1559 Test Apparatus ................................................................. 20
2. Typical Mounting bracket for the 4 QCMs used in the E1559 Test Method ............... 21
3. Typical deposition curves for a material tested using the ASTM E-1559 Test Standard Procedure ........................................................................................................... 22
4. Typical Thermo gravimetric procedure test results .................................................. 23
5. Comparison of deposition data taken during Round-Robin series of tests for Butyl Orings ................................................................................................................. 24
6. Comparison of deposition data taken during Round-Robin series of tests for Polyethylene beads ......................................................................................................... 25
7. Comparison of thermo gravimetric data taken during Round-Robin series of tests for Butyl Orings ......................................................................................................... 25
8. Comparison of thermo gravimetric data taken during Round-Robin series of tests for Polyethylene beads ......................................................................................................... 26
9. Calculated values (using CALCRT) for reflectance and transmittance for film thicknesses formed from condensed outgassing products from Polyclad on a germanium window for a wavenumber of 2000 cm⁻¹ (wavelength = 5 microns) .............................................................................. 26
10. Calculated values (using CALCRT) for reflectance and transmittance for film thicknesses formed from condensed outgassing products from Uralane on a germanium window for a wavenumber of 3000 cm⁻¹ (wavelength = 3.33 microns) .......................................................... 27
11. Calculated values (using CALCRT) for reflectance and transmittance for a one micron thick film formed from condensed outgassing products from ChemglazeA276 on a germanium window as a function of wavenumber .......................................................... 28
LIST OF TABLES

1. Summary of the facility and QCM operational characteristics .................................................. 18

2. Tabulated results of the Round-Robin series of E1559 outgassing tests for Butyl O-rings and Polyethylene beads. ................................................................. 19
I.  Introduction

This report describes the results of an NRA funded program entitled “Space Environmental Effects Knowledgebase” that received funding through a NASA NRA (NRA8-31) and was monitored by personnel in the NASA Space Environmental Effects (SEE) Program. The NASA Project number was 02029.

The Satellite Contamination and Materials Outgassing Knowledgebase (SCMOK) was created as a part of the earlier NRA8-20 (Ref. 1). One of the previous tasks was to accumulate data from facilities using QCMs to measure the outgassing data for satellite materials. A special emphasis was placed on datasets taken using the ASTM E-1559 satellite materials outgassing standard. A user friendly database platform compatible with SEE requirements was established to input the data into separate, linked databases, and this Knowledgebase was then turned over to the NASA/SEE Program office. This Knowledgebase also included data and references in which space flight data using QCMs were available.

NRA8-31 provided an opportunity to essentially double the amount of E1559 information included in the Knowledgebase. Large NASA programs such as the International Space Station (ISS), James Webb Space Telescope (JWST), and Living With a Star (LWS) utilize newly developed materials. These materials outgassing datasets for the newer materials from various facilities should be especially beneficial to these programs. The main objective of this current program was to increase the number of material outgassing datasets from 250 up to ~ 500. As a part of this effort, a round-robin series of materials outgassing measurements program was executed that allowed comparison of the results for the same materials tested in 10 different test facilities.

Other program tasks included obtaining datasets or information packages for 1) optical effects of contaminants on optical surfaces, thermal radiators, and sensor systems and 2) space environmental effects on surfaces and materials. These tasks included the collection of contamination optical property data and related space environmental effects data and incorporating these data into the already existing NASA/SEE Knowledgebase. Previously, the emphasis was on the collection of only QCM related data but as a part of this program, the Knowledgebase was expanded to include the contamination and optical effects data. The Knowledgebase was modified to include data from these two additional topics. In many mission areas contamination of sensors and optics is a continuing concern. The E1559, optical effects, space environmental effects, and flight QCM data will undoubtedly be beneficial to those programs through the availability of materials outgassing data and the contaminant optical and space environmental effects information. More than 150 requests for access to this Knowledgebase have already been processed through the NASA/SEE Program office.

Initially, the SCMOK could be accessed online by obtaining the appropriate login name and password from the NASA/SEE program office. Due to several problems associated with hackers, NASA decided to protect the SCMOK by restricting access to only those in need of this information. This wasn’t the preferred course of action but it did provide access to those who needed it with considerably
more control and at the same time eliminated the hacker problems. This new method of access to the Knowledgebase provided the user with a CD containing all of the information previously accessible online. The new method also required that the user have access to the Internet Information Service (IIS) which meant that the user’s computer operating system had to be either Windows 98, Windows 2000, or Windows XP Professional. Based on the original sets of data, the CD system was satisfactory but as more data was added, the CD was no longer capable of storing all the necessary data. A DVD is now available to users that contains all of the added data accumulated throughout this current program.
II. Structure of the Satellite Contamination and Materials Outgassing Knowledgebase

A) Material Outgassing Data

B) Round-Robin Material Outgassing Results
C) Flight QCM Data
D) Midcourse Space Experiment (MSX) Spacecraft
E) Optical Properties of Contaminant Films at Cryogenic Temperatures
F) Space Environmental Effects

A) Material Outgassing Data

The ASTM-1559 Standard test method was first established in 1993 as an improved version of the ASTM E595 Standard for measurement of material outgassing. The older E595 method was originally designed as a screening technique to determine the suitability of materials for space flight. The total mass loss (TML) of the materials was determined by weighing the material samples beforehand, heating them to 125°C for 24 hours under vacuum, and reweighing them after removal from the vacuum chamber. The loss in mass was divided by the original mass to get the percentage TML. However, this standard has been used far beyond its original intent to provide information related to the screening of materials for use in space. In order to provide a method for the characterization of materials outgassing kinetics, E1559 was established. It has now been adopted in many programs for screening materials that are to be used in space applications. The outgassing raw data are converted to TML and collected volatile condensable material (CVCM) levels.

Test Method E1559 uses a method that allows the total mass loss to be determined through the use of 3 to 4 quartz crystal microbalances cooled to various temperatures. Figure 1 shows a typical experimental arrangement used in making the outgassing measurements. Two methods (A and B) may be used for determining the outgassing kinetics. In method A, specific QCM and specimen temperatures as well as geometry of the source/receiver are required, whereas in method B, there is considerable flexibility in the temperatures that can be used and even in the test geometry. Test Method A requires that three of the QCMs be maintained at 90, 160, and 298K. One other QCM operating at a different temperature can be used, but is not required. Although an effusion cell temperature of 125°C typically is used for Method A, other temperatures can be used in Method B that may be more closely related to the actual operational material temperatures. One version of the QCM mounting fixture used for E1559 testing is shown in Figure 2.

The test chamber is evacuated to a vacuum level on the order of $10^{-8}$ torr before QCM cooling is commenced. The QCMs are maintained at approximately 300K until the chamber liner and baffles have reached temperatures of less than approximately 75K. At this point the heaters to the QCMs are commanded to set point temperatures varying from 77K for the coldest to as high as 298K for the warmest. The QCMs are thermally shielded from each other to allow the temperatures to be independently controlled. Once these temperatures have become constant, outgassing data can be collected. The sample material, on the order of 10 to 20 grams, is placed inside the effusion cell and mounted in the interlock chamber. After the interlock chamber has been evacuated to a level of approximately $10^{-7}$
torr, the interlock valve is opened and the effusion cell moved to the location where the orifice is 150 mm from each of the QCM sensing crystals. Once this location has been established, the effusion cell temperature controller is set to the desired temperature – usually 75 to 125°C, and the QCM frequencies recorded as a function of time. The time required for completion of an outgassing test varies depending on the needs of the user. In many instances outgassing times of up to 6 days are used in order to determine the long-term outgassing rates. Typical deposition curves for a material tested using the E-1559 standard procedure is shown in Figure 3.

After the condensed mass of the outgassing products has reached a plateau, the effusion cell is withdrawn from the chamber and back into the interlock chamber. At this point the QCM temperatures are commanded to a much warmer temperature, usually 125°C, to boil off the condensed contaminants. A warmup rate of 1°C/min is suggested in E1559. Using this thermogravimetric procedure allows one to collect valuable information as to the various species condensed as well as the deposition and evaporation temperatures of each specie (See Figure 4).

Upon completion of the testing, the material test sample is removed from the effusion cell and weighed. The value obtained is compared to the value prior to the start of the outgassing measurements. The total mass loss is determined from these data and then compared with that obtained from the calculated values determined using the QCM deposition data.

During NASA NRA8-31 approximately 275 additional datasets have been added to the SCMOK during this program. The following have provided these data:

1) NASA Goddard -- Molekit Chambers (George Meadows and Randy Hedgeland)
2) NASA Goddard – Molidep Chamber (Alex Montoya and John Scialdone)
3) Lockheed Space and Missiles Chambers (Stainless Steel and Bell Jar) (Eric Lay and Norbert Ching)
4) OSI – Chambers A and B (Jeff Garrett and Doug McCroskey)
5) Agilent – (Vijaya Raghavan and Mark Sullivan)
6) AEDC – 20K Facility (Bill Bertrand)
7) Marshall Space Flight Center (Keith Albyn)

A listing of all material outgassing datasets obtained during this program is given in Appendix 1. A typical dataset contains the following:

A) An Excel file (.xls) containing all of the available data collected during the test. This includes the data for all of the QCMs that were available. Multiple plots are also included. Since these are relatively large files, they are downloaded as zipped files.

B) An Excel file (.csv) which contains only the Time, Temperature, and QCM Frequency for each of the QCMs. No plots are included. This file is mainly used for the Java online plotting routine.

C) A pdf file that describes the materials and test conditions
D) Usually 1-4 gif files (images) are included that are figures of the frequency vs time deposition data or the thermogravimetric analysis (TGA) warmup data. This provides a quick overview of the results without having to download the larger files.

B) Round-Robin Material Outgassing Tests

One of the suggestions made by previous users of the SCMOK was to provide a comparison of data taken at different facilities by performing a round-robin series of tests. The objective of a round robin series of tests was to quantify the variations observed within each facility and between facilities. A round-robin series of testing was completed during 2004 in which ASTM E1559 type measurements were in ten different measurement facilities that included OSI (2), NASA/GSFC (3), Lockheed/Martin (2), AEDC, Agilent and NASA/MSFC. Measurements were made on two materials that were chosen based on several factors. It was desirable to provide samples to the test facilities that were already prepared so there wouldn’t be any differences in the sample preparations. The samples were also chosen to have outgassing properties that would allow condensation of all species on each of the QCMs that were maintained at 80, 160, 220, and 298K. A summary of the facility and QCM operational characteristics are provided in Table 1.

The test samples provided for the ASTM E 1559 Round-Robin test consisted of two materials – polyethylene beads and Parker Butyl B612-70 O-rings. The raw materials were obtained from Jeff Garrett at OSI in Palo Alto, CA. Jeff is a member of the ASTM E 21.05 committee that oversees the ASTM E 1559 standard test method. Vials containing the samples were distributed to the participating facilities and contained ~ 1 gram of polyethylene beads and ~ 2 grams of butyl O-rings. Each vial contained enough material for one test. Extra vials were provided just in case some malfunction should occur during the test and a restart required. The participants contributed their time and facilities to make this Round-Robin effort possible. This test series helped to quantify E1559 measurements accuracy and any systematic variations between facilities.

Material outgassing tests were performed per the ASTM E 1559 test method with QCM temperatures at <90 K, 160 K, 220 K, and 298 K. Both samples were tested at an effusion cell temperature of 125°C and the duration of each test was 72 hours. Test data including the QCM frequencies and temperatures, as well as the reduced data (Total Mass Loss, Volatile Condensable Material, etc.) were submitted as Excel data files. Test information such as sample mass, sample dimensions, QCM type and sensitivity, apparatus view factors, and any exceptions to the ASTM method were also included. Similarly, the thermogravimetric test (TGA) data were included as a separate Excel Work Sheet within the Excel file.

Description of the Round-Robin Samples

**Parker Butyl B612-70 O-Rings**
Parker Size – 2-203
ID = 0.296 inches, W = 0.139 inches
Nominal size = 5/16” x 1/8 “
Surface Area per O-Ring = 3.85 cm²
**High Density Polyethylene Beads**
Lot #19  
CAS # 25213-02-9  
CAT # 041  
ID = 0.125”  
Length = 0.155”

Figure 5 shows a comparison of the deposition data taken during the Round-Robin series of testing for the Butyl O-rings. The QCM temperature for all of these curves was ~ 90K so this data serves as the Total Mass Loss (TML) data. The total change in frequency (Delta Frequency) for 7 of the 9 facilities over the 72 hour outgassing time was between 14,000 and 16,000 Hz depending on the facility. The two curves that overlay at the top of the graph were from the NASA/GSFC Molekit facilities that used a non-standard effusion cell aperture which allowed more outgassed material to be collected by the QCMs. However, the TML and CVCM values determined in the Molekit facilities were in good agreement with the values determined from the other facilities, see Table 2.

Similarly, Figure 6 shows a comparison of the deposition data taken during the Round-Robin E1559 tests for Polyethylene beads. Seven of the 9 facilities had a delta frequency varying between about 1700-1900 Hz with the GSFC data being considerably higher for the reason explained earlier.

The facilities that used the ASTM E1559 method for calculating TML were AEDC, Agilent, Lockheed, and OSI. The CVCM values for MSFC were calculated using this method. As can be seen from comparison of the data in Table 2, there is good agreement of the outgassing results for all of the facilities for both TML and CVCM values.

At the conclusion of each outgassing test, the coldest QCM was warmed up to 400K using an internal QCM heater. The TGA curves for the Butyl O-rings and Polyethylene beads are shown in Figures 7 and 8, respectively. The different species condensed from the Butyl O-rings in Fig. 7 can be seen by the different inflections in the curves as the temperature is increased.

C) **Flight QCM Data**

QCMs have been flown on many spacecraft for the purpose of measuring the contamination levels at various locations on or about the spacecraft or to measure atomic oxygen levels. The objective of this effort was to locate those flight experiments that had QCMs on board and to make available the data collected during those flights. In some instances processed or raw QCM data have been included whereas in other instances only papers or reports describing the results were available. The data have been subdivided into Shuttle and Satellite subsets. The NASA shuttle program has had several missions on which quartz crystal microbalances (QCMs) were flown. NASA shuttle flights containing QCM experiments have been researched to provide summaries of the data that were collected as part of each mission in which QCM data was available. The QCMs were used for either monitoring contamination deposition or the measurement of environmental effects - such as atomic oxygen. In the early days of the shuttle, the Induced Environment Contamination Monitor (IECM) was developed by NASA and flown on flights STS 2,3,4, and 9, with QCMs being part of the instrument package. Another monitoring package, the Contamination Monitoring Package (CMP) was a smaller version and was flown on flights...
STS 3, 8, and 11. An Environment Monitoring Package (EMP) containing QCMs for measuring atomic oxygen was flown on STS-46 as part of EOIM 3. A Contamination Environment Package (CEP) was flown on STS-82 for measuring contamination in the vicinity of the Hubble Telescope during the second servicing mission.

The satellite QCM datasets are for missions that required much longer times in space than for the typical NASA shuttle experiments. Typically, exposure times for these missions were measured in months or years. Included in this section are results from the Russian Mir Space Station and eventually the International Space Station.

D) MSX Satellite Program

The Midcourse Space Experiment (MSX) satellite was launched into a 903 Km, 99.4-deg orbit from Vandenberg Air Force Base on April 24, 1996. This section provides tabulated quartz crystal microbalance (QCM) data that were accumulated over the first 20 mission months in space. Technical summaries, reports and papers are available for all of the contamination measuring onboard instruments. The QCM data collection was stopped on August 25, 2004 after more than 8 years of operation in space. MSX is the only known space flight experiment that has provided continuous contamination monitoring for this extended length of time.

The MSX satellite program was funded by the Ballistic Missile Defense Organization (BMDO). The MSX satellite was part of a demonstration/validation program which had both defense and civilian applications. With telescopes and imagers operating in the wavelength range from the UV through the infrared spectrum, data from the spacecraft were used in the identification and tracking of ballistic missiles during midcourse flight. Data were also collected for test targets and space background phenomena. The MSX program provided an opportunity to monitor in-flight contamination and to investigate the composition and dynamics of the Earth’s atmosphere. The UV-Visible data were collected by a suite of four imagers and five spectrographic imagers (UVISI) which were operating in wavelength segments from 110 – 900 nm. Visible and near IR data were collected by the Space-Based Visible (SBV) sensor system which was comprised of a CCD camera operating in the 400 – 1000 nm wavelength range. Both UVISI and SBV sensor systems operated over the –20C to +30C temperature range.

The other major sensor system was the Spatial Infrared Imaging Telescope (SPIRIT 3). It was a cryogenic telescope that was cooled from an onboard dewar of solid hydrogen with component temperatures ranging from 8.5K up to 65K depending on their location and spacecraft orientation. A gold coated sun shield was placed near the entrance of SPIRIT 3 to protect against unwanted solar radiation getting into the telescope. It should be noted that all of the science instruments were located on the +X face of the spacecraft with the electronics placed near the –X face at the other end of the spacecraft. This was designed to minimize contaminants outgassing from warm electronic boxes and condensing on science instrument surfaces. A contamination control plan was followed throughout the mission to minimize contamination levels on orbit. Based on results from all of the contamination instruments, this goal was achieved.
The MSX organization was comprised of 8 scientific/technical teams for the functional areas of 1) Early Midcourse Targets 2) Late Midcourse Targets 3) Space Surveillance 4) Earthlimb Backgrounds 5) Shortwave Terrestrial Backgrounds 6) Celestial Backgrounds 7) Data Certification and Technology Transfer and 8) Contamination. Each of these principal investigator teams was responsible for designing experiments, providing necessary flight instrumentation, and performing analysis of the ground calibration and flight data.

The Contamination Experiment was comprised of using a suite of instruments for monitoring various aspects of contamination around and within the spacecraft. These instruments included a total pressure sensor (TPS), neutral and ion mass spectrometers, krypton and xenon flashlamps for measuring water molecular density and particulates, respectively, 4 temperature controlled qcms (TQCMs) and one cryogenic QCM (CQCM) that was located inside the SPIRIT 3 cryogenic telescope. With these instruments it was possible to characterize the time varying health of the spacecraft throughout its mission.

The 5 QCMs on board the satellite have provided on-orbit data that have been invaluable in characterizing contamination levels around the spacecraft and inside the SPIRIT 3 cryogenic telescope. The CQCM was located internal to the SPIRIT 3 cryogenic telescope, was mounted adjacent to the primary mirror, and provided contamination accretion measurements during the 10 month lifetime of SPIRIT 3. Real-time monitoring of contaminant mass deposition on the primary mirror was provided by this CQCM which was cooled to the same temperature as the mirror -- ~20K. Thermogravimetric analyses (TGAs) on the CQCM provided insight into the amount and species of contaminants condensed on the SPIRIT 3 primary mirror during various spacecraft activities.

The 4 temperature controlled QCMs (TQCMs) were mounted on external surfaces of the spacecraft for monitoring contaminant deposition. The TQCMs operated at ~ -50C and were positioned strategically to monitor the silicone and organic contaminant flux arriving at specific locations.

The data downlinked for the contamination related experiments was of two types. Two tape recorders were used to record data for individual experiments and about 10 minutes of real time data was downlinked each orbit from the spacecraft to the receiving station at the Johns Hopkins University / Applied Physics Laboratory (JHU/APL). The MSX spacecraft makes one revolution about the earth in about 102 minutes. Therefore, the real-time data were downlinked approximately 15 times per day. The tape recorder data were also downlinked during the passes over JHU/APL.

MSX stayed in its parked mode orientation for most of the time. In this mode, the -Y face of MSX was facing towards the sun for maximum power generation by the solar panels. The +Z face was into ram and the -X face was always facing earth. The +X direction was always perpendicular to the sun vector and looking out and away from earth to minimize thermal loading on the Spirit 3 telescope. Generally, the spacecraft remained in the parked mode prior to spacecraft maneuvers for dedicated experiments that required other orientations. Upon completion of the data collection event, the spacecraft was returned to the parked mode.

A paper describing the 8+ years of QCM data was presented at the 43rd AIAA Aerospace Sciences Meeting, AIAA paper No. 2005-0067. A summary of the complete QCM data time histories
of the contaminant thickness deposition for each of the QCMs is available in Ref. 2. Approximately 90 papers describing results of the MSX program are included in pdf format in the Knowledgebase and can be accessed through two different searchable methods.

**E) Optical Properties of Contaminant Films at Cryogenic Temperatures**

In this section, optical properties (refractive and absorptive indices) are provided for contaminant films condensed at cryogenic temperatures between 20K and 77K. Designers of telescopes that require cryogenic optics and sensors are especially concerned with the condensation of contaminants that can alter the reflective or transmissive characteristics of a sensor system. Most of these telescopes operate in the infrared region – therefore, all of the indices presented here are for the wavenumber range from about 3700 – 700 (wavelength range from about 2.7 µm to 14 µm). The contaminant films investigated fall into 3 categories:

1) Films formed from pure gases such as CO₂, H₂O, NH₃, CO and others

2) Films formed from outgassing products from spacecraft materials such as composites, paints, films, or silicones

3) Films formed from bipropellant gases and plume exhaust products – such as hydrazine, nitrogen tetroxide, monomethyl hydrazine

These optical properties were determined from laboratory measurements made at the Arnold Engineering Development Center (AEDC) at the Arnold Air Force Base in Tennessee by Dr. Jeffrey A. Roux and Bobby E. Wood. These properties have been used to support space-based optical systems such as cryogenic telescopes for both defense and civilian efforts.

The refractive and absorptive indices (n’s and k’s) were determined by condensing the films on a cryogenically cooled germanium window, and measuring the transmittances of the window plus films (See References 3-10). This was done for films varying in thickness from about 0.12 um up to a maximum of about 5 microns. For each material, transmittance measurements were made for 10 – 25 film thicknesses depending on the experimental conditions caused by the unique behavior of each material. An infrared interferometer-spectrometer was used in determining the transmittance values. All of the transmittance spectra for each material were combined with a program called TRNLIN (developed by Dr. J.A. Roux) that used a non-linear least-squares curve fit to determine the refractive and absorptive indices. The non-linear option was required due to the optical interference exhibited by the thin films. In some special cases, a Subtractive Kramers-Kronig technique was used to determine refractive indices.

The equations used and details involved in determining these n and k properties can be found in References 6-9.

To realize the maximum utility of the data (n’s and k’s) generated from the experimental and analytical studies, it was necessary to develop another computer program. A model was developed that allows one to calculate the effects of these contaminant films on other optical surfaces. This program
CALCRT was developed by Dr. Kent Palmer of Westminster College in Fulton, Missouri (while under contract to the Arnold Air Force Base) to allow such calculations. The acronym CALCRT stands for the Calculation of Reflectance and Transmittance. The reflectance and transmittance of an optical element can be calculated as a function of wavelength, incidence angle, contaminant film thickness, and substrate. The user must supply the substrate optical constants and thickness, the contaminant optical constants and thicknesses, and the radiation beam incidence angle. The executable DOS version of this model (CALCRT.exe) can be downloaded to your PC. Instructions to help run this program are included in the files that can be downloaded. Some results of the use of CALCRT are presented in References 11 and 12.

Examples of contaminant effects calculated using CALCRT are shown in Figs. 9-11. Figure 9 shows the reflectance/transmittance values for contaminant films condensed on a germanium window. The condensate was deposited at 77K and was composed of the outgassing products from Polyclad. The data are for a wavenumber of 2000 cm\(^{-1}\) or 5.0 microns wavelength. Figure 10 shows similar data taken at 3000 cm\(^{-1}\) or 3.33 microns wavelength for outgassing products from Uralane. Figure 11 shows the reflectance/transmittance of 77K germanium with a 1 micron thick contaminant film deposited from the outgassing products of Chemglaze A276 paint. These types of calculated spectra can be accomplished using the CALCRT program and refractive/absorptive indices for any of the contaminants listed in Appendix 2.

**Space Environmental Effects**

To survive in the space environment one has to contend with ultra-violet radiation, atomic oxygen, materials outgassing, plumes, protons, electrons, plasmas, spacecraft charging, micrometeorites, space debris, vacuum, and the cold black 4K background. There is considerable information regarding the effects of the space environment on surfaces, instruments, and spacecraft. This includes both space flight data and ground simulation data. In this section, many of the previously written papers/reports describing these effects have been included in a single database. The database includes extensive data for the LDEF program (all of the information available from all three post-retrieval conferences) and from other programs such as MIR, POSA, MSX, and others. Including the approximately 100 papers previously available, there are now approximately 300 papers/reports that can be accessed through the Knowledgebase. The papers/reports are now available in PDF format and can be accessed using Acrobat (preferably 6.0 or 7.0). The Acrobat 7.0 Reader is now available and can be downloaded free of charge from the following website: [http://www.adobe.com/products/acrobat/readstep2.html](http://www.adobe.com/products/acrobat/readstep2.html).

Two different search routines are provided in the Knowledgebase. One uses the Global Search routine that has been used previously with the MSX papers/reports and the other is the ‘Search SEE Paper’ using the Acrobat 6.0 search index.

Some of the more notable recently added reports to the Knowledgebase and now in PDF form include:

- LDEF -- 69Months in space Part 1
- LDEF -- 69Months in space Part 2
- LDEF -- 69Months in space Part 3
- LDEF – Second Post Retrieval Part 1
This collection of contamination and space environmental effects papers makes this an ideal starting point for anyone needing to review past
III. **To obtain your copy of the Space Environment Effects Knowledgebase**

In order to meet export control and maintain the integrity of the NASA models, the SEE Program has agreed to review the provided information and perform the necessary paperwork. All models are executable only and the source code can only be obtained by contacting the SEE Program Office.

**Before access is granted, you must send to NASA the following TWO forms:**

1. **SEE Product Access Form** (submit thru online)

2. **Software Usage Agreement (SUA) Form/s** (link below) - hardcopy of the form must be completed, signed, and FAX to Sopo Yung at 256-544-8807

3. Link to SUA: [http://see.msfc.nasa.gov/ModelDB/outgassing_sra.htm](http://see.msfc.nasa.gov/ModelDB/outgassing_sra.htm)
IV. Summary

The main four objectives for this program were the following:

(1) Expand and improve the existing Satellite Contamination and Materials Outgassing and Effects Knowledgebase. Include available material outgassing data for newer materials would increase the knowledgebase from ~250 to ~500 materials.

(2) Develop an electronic knowledgebase that addresses the issue of space environmental effects on surfaces and spacecraft. This was to include effects of absorption and reflectance due to contaminants on surfaces in the presence of AO, UV, radiation, etc.

(3) Develop a spectral library of the optical properties of contaminant films on optical and thermal control surfaces. This would include characteristics, absorption, and emission for typical contaminants that might be encountered in space.

(4) Establish a round-robin test program for material outgassing test facilities that use the ASTM E1559 Materials Outgassing Test Method. This would provide a measure of the confidence one could assume by testing at any of the laboratories at which these types of measurements are made.

All four of these objectives were met. Currently the materials outgassing section of the Knowledgebase contains ~575 datasets for materials tested using the E1559 standard plus another 100 or so that used a modified version by the European Space Agency. Material outgassing data were obtained from 10 different facilities using during this program.

The refractive and absorptive indices for thin films of gases condensed at 20-77K are presented in tabular form. This includes data for 50 sources such as pure gases (e.g. water, CO2, NH3 and others), mixtures of these, gases from rocket engine plumes, and satellite material outgassing products. These data are available through the Knowledgebase along with a thin film software program (CALCRT) for calculating the effects of these films on an optical surface reflectance or transmittance.

Electronic or PDF files for approximately 200 additional papers/reports relating to space environmental effects was added to the Knowledgebase. This included many papers concerning LDEF, POSA, MIR, MSX, and other satellite programs. This should provide an opportunity for one to review much of the work accomplished in the past at a single location.

One of the shortcomings of the earlier version of the knowledgebase reported by previous users was that comparison of material outgassing data obtained between various E1559 measurement facilities was extremely difficult. To remedy this problem a round-robin series of testing was established which included E1559 type measurements being made by measurement facilities at OSI, NASA/GSFC, Lockheed/Martin, NASA/MSFC, Agilent, and AEDC. This round-robin series consisted of testing the
outgassing from two materials (Butyl O-rings and Polyethylene Beads) at 125°C for 72 hours. All of the test data were provided to BWACS, Inc. where the data were processed, analyzed, and summarized and will be reported at an upcoming technical conference. The results currently exist in the Knowledgebase.

Plans were to include some of the results of the MISSE and GENESIS programs in the Space Environment Effects portion of the Knowledgebase. However, MISSE has not yet been returned from the ISS and the GENESIS results were not available at the time of this contract end.

Large NASA programs such as the International Space Station (ISS), James Webb Space Telescope (JWST), and Living With a Star (LWS) can utilize the data for the newly developed materials. Since the data included in each of these databases will be beneficial to Spacecraft Systems, Instrument Systems, and Communication Systems, this effort is an example of a crosscutting technology with applications to the Space and Planetary, Development of Space, Earth Science, and Commercial Remote Sensing NASA Customer Mission areas. In each of these mission areas contamination of sensors and optics is a continuing concern. Although not specifically aimed at the Living with a Star Program (LWS), the E1559, Flight QCM, and Space Environment Effects data will undoubtedly be beneficial to that program also through the availability of materials outgassing and contaminant optical and space environmental effects information.
V. Acknowledgements:
The author would like to acknowledge the following:

A) Jody Minor, Billy Kauffman and Robby Newton of the NASA/SEE Program Office, Sopo Yung of Morgan Research, and Gayle Brown of USRA for their support in carrying out this program.

B) USRA students Nicholas Segraves, Kyle Brickhouse, and Jason Baxley for helping with the inputting of the data into the Knowledgebase.

C) Tom Carson of the New Economy Institute (NEI) in Chattanooga, TN and NEI employees who assisted the author in converting many of the documents relating to space environmental effects on spacecraft into pdf files. Those participating included: Tom Carson and Lyn Price – NEI staff, Angela Milton, Robert Smith, Katie Lane, Heather Rogers – NEI Interns, John Carson – Contract Scanner, and Chris Carson -- Boy Scout Volunteer for Merit Badge Project.


E) Dr. B. David Green of Physical Sciences Incorporated for support and assistance in executing the goals of the project.
References:


Table 1: Summary of the facility and QCM operational characteristics

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<th>QCM</th>
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<th>Frequency</th>
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<th>QCM Vendor</th>
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Table 2. Tabulated results of the Round-Robin series of E1559 outgassing tests for Butyl O-rings and Polyethylene beads.

### Butyl O-Rings

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<th>TML(80K), %</th>
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<td>Lockheed – SS -Lay</td>
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* Measured by weighing before and after outgassing
** Used Cahn Microbalance

### Polyethylene Beads

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* Measured by weighing before and after outgassing
** Used Cahn Microbalance
Fig. 1 Typical ASTM E-1559 Test Apparatus
Fig. 2 Typical Mounting bracket for the 4 QCMs used in the E1559 Test Method
Fig 3  Typical deposition curves for a material tested using the ASTM E-1559 Test Standard Procedure.
Fig. 4 Typical Thermo gravimetric procedure test results
Fig. 5 Comparison of deposition data taken during Round-Robin series of tests for Butyl Orings.
Fig. 6 Comparison of deposition data taken during Round-Robin series of tests for Polyethylene beads.

Fig. 7 Comparison of thermo gravimetric data taken during Round-Robin series of tests for Butyl Orings.
Figure 8  Comparison of thermo gravimetric data taken during Round-Robin series of tests for Polyethylene beads.

Fig. 9  Calculated values (using CALCRT) for reflectance and transmittance for film thicknesses formed from condensed outgassing products from Polyclad on a germanium window for a wavenumber of 2000 cm\(^{-1}\) (wavelength = 5 microns).
Fig. 10 Calculated values (using CALCRT) for reflectance and transmittance for film thicknesses formed from condensed outgassing products from Uralane on a germanium window for a wavenumber of 3000 cm⁻¹ (wavelength = 3.33 microns).
Fig. 11 Calculated values (using CALCRT) for reflectance and transmittance for a one micron thick film formed from condensed outgassing products from ChemglazeA276 on a germanium window as a function of wavenumber.
Appendix 1:

Listing of E1559 outgassing data for new materials added to the Knowledgebase during this program

Key to Facility Providers:
AGI --- Agilent
AEDC – AEDC, Arnold AFB, TN
JSC—Johnson Space Center
OSI – Outgassing Services International
GSFC- Goddard Space Flight Center – Molekit
GSFC- Molidep – Goddard Space Flight Center -- Molidep
LMSC—Lockheed Space and Missiles Company
MSFC -- Marshall Space Flight Center

<table>
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<th>Material Name</th>
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<td>3M Scotchweld</td>
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<td>303 Stainless Steel at 30C</td>
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<tr>
<td>DC6-1104 at 343K</td>
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<td>Invar FM at 303K</td>
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<td>Lexan 500 Injection Molded Plastic at 303K</td>
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<td>Noryl EN 265-701 IM Plastic</td>
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<td>Stainless Steel 416</td>
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<td>Valox 420 BK 1066 Injection Molded Plastic at 303K</td>
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<td>Varian Torr Seal at 303K</td>
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<td>Hysol Epoxy Paste at 423K</td>
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Kapton Tape at 383K  JSC
Kapton Tape at 423K  JSC
High Air Velcro – 110C  JSC
High Air Velcro – 150C  JSC
HTSCE – 50C  JSC
Kevlar Epoxy -- Alenia --398K – No Preconditioning  JSC
Kevlar Epoxy – Alenia -- 398K -- 100 Hours of preconditioning  JSC
Kevlar Epoxy – Alenia -- 398K – 200 Hours of preconditioning  JSC
Kevlar Epoxy – Alenia -- 398K – 300 Hours of preconditioning  JSC
Kevlar Epoxy – Alenia -- 428K  JSC
Kynar – 300K  JSC
Kynar -- 325K  JSC
Kynar -- 355K  JSC
Nextel -- Alenia -- 150C no preconditioning  JSC
Nextel -- Alenia -- 150C preconditioning  JSC
Nomex Velcro – 80C  JSC
Nomex Velcro – 110C  JSC
RTV 560 – 50C  JSC
Teflon 52C  JSC

Chemglas 250F Betacloth @30C  OSI
Chemglas 250F Betacloth @75C  OSI
Chemglas 250F Betacloth @125C  OSI
Chemglas 500F Betacloth @30C  OSI
Chemglas 500F Betacloth @75C  OSI
Chemglas 500F Betacloth @125C  OSI
CombiTherm VPC 07 @43C  OSI
CombiTherm VPC 07 @68C  OSI
CombiTherm VPC 07 @102C  OSI
Derakane 470HT @50C  OSI
GE RTV 142 @75C  OSI
GE RTV 142 @90C  OSI
GE RTV 142 @125C  OSI
Hi-Temp Velcro HT-1773 @51.7C  OSI
Hi-Temp Velcro HT-1773 @81.2C  OSI
Hi-Temp Velcro HT-1773 @110C  OSI
Kevlar 29 @ 32C  OSI
Kevlar Epoxy Unbaked @80C  OSI
Kevlar Epoxy Unbaked @100C  OSI
Nextel 312 –8-95 @33C  OSI
Nextel 312 (600C Prebake) @150C (Large sample Prebaked)  OSI
Nextel 312 (600C Prebake) @150C (No Prebake)  OSI
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Lacquer on Aluminum @30C
Chemglaze Z306 + primer on Al @10C
Chemglaze Z306 Al Substrate @10C
Chemglaze Z306 – No primer on Al @10C
Urelane 5753 Mix 2 @30C
NS43C on Al Foil @80C
Gap Pad VO (yellow) @40C
Gap Pad VO Soft (Pink) @40C
Gap Pad VO Soft (Pink) Air Baked @40C
Gap Pad VO (Yellow) Air Baked @40C
P-touch Label Tape @30C
CdZnTe Detector @15 and 30C
9 Pin D Connector + Wires @80C #2
Chemglaze Z306 + Primer on Al @80C
Chemglaze Z306 Al Foil @80C
Oil-Contaminated Nickel Foil @25C
Chemglaze Z306 + Primer on Al @50C
Chemglaze Z306 + Primer on Al @30C
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Chemglaze Z306 on Al @50C
RTV566 @30C
Unbaked NSB 6982 @102C
Al Foil @102C
RTV566 @10C
Urelane 5753 Mix 1 @70C
Urelane 5753 Mix 1 @30C
Urelane 5753 Mix 1 @30C #2
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Urelane 5753 Mix 2 @30C
Al Substrate @80C
Aluminized Kapton @30C
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Aluminized Kapton @80C
Bare Kapton @30C
Bare Kapton @50C
Bare Kapton @80C
Chemglaze Z306 on Al @30C
Lacquer on Al @80C
Lacquer Al Substrate @80C
Chemglaze Z306 + Primer on Al @10C
QCM Verification with Cetyl Alcohol
Carbon Phenolic Nozzle @300C
RTV157 on Cloth Backing @35C
Aptek 2706 on Al @75C
EC2216 @80C
Carbon Phenolic Nozzle @100C
Carbon Phenolic Nozzle @200C
Carbon Phenolic Nozzle @200C #2
Lacquer on Al Foil @80C
Lacquer on Al Foil VDA Overcoat @80C
Al Foil Substrate VDA Lacquer @80C
Al Substrate Lacquer Test @80C
EC2216 @30C
EC2216 @50C
Exposed RTV560 @20C
Exposed RTV560 @20C RGA
RTV566 @30C
VEC Sample @75C
Black Cable Sleeve @80C
Black Cable Sleeve @50C
Black Cable Sleeve @30C
Black Cable Sleeve @80C #2
Exposed Puck Adsorber @30C
Exposed Puck Adsorber @50C
Exposed Puck Adsorber @80C
Exposed Puck Adsorber @100C
Teflon Cable @80C RGA
Teflon Cable @80C no RGA
9 Pin D Connector + 6 Wires @80C
9 Pin D Connector + 6 Wires @30C
RTV566 @80C
Exposed Puck Adsorber @30C #2
Exposed Puck Adsorber @50C #2
Exposed Puck Adsorber @80C #2
Exposed Puck Adsorber @100C #2
Exposed Puck Adsorber @125C
Exposed Puck Adsorber @150C
Variable Emittance Sample (split) @25C
Exposed RTV560 @40C
9 Pin D Connector + 6 Wires @80C #2
2 Conductor Teflon Cable @80C
2 Conductor Teflon Cable @30C
CV1142 @125C
CV1142 @75C
CV1142 @125C #2
9 Pin D Connector + 2 Conductor Cable @30C
9 Pin D Connector + 2 Conductor Cable @50C
9 Pin D Connector + 2 Conductor Cable @80C
Laminated Brass Washers @ 40C
RTV 142 Epoxy @15C

GSFC
RTV 142 Epoxy @30C
Teflon Cable @80C
Teflon Cable @50C
Teflon Cable @30C
Teflon Cable @80C #2
Teflon Cable @50C #2
Epotek 410E @15C
Epotek 410E @30C
Adsorber Puck Cleaning
Exposed RTV 560 @20C
Exposed RTV 560 @50C
Pennzane 2000 + Pb Napthenate @30C
Twisted Teflon Wire @80C
Twisted Teflon Wire @30C
9 Pin D Connector + 6 Teflon Wires @80C
9 Pin D Connector + 6 Teflon Wires @50C
CV-2289@30C
Sil-Pad @30C
Sil-Pad @50C
Aluminized Blanket @200 and 350C
Polyimide Printed Board @ 0C
Polyimide Printed Board @ 20C
Polyimide Printed Board @ 60C
Variable Emittance Sample @25C
Variable Emittance Sample @50C
Variable Emittance Sample @70C
Shuttle Panel B KP1A276@20C
Shuttle Panel C KP2A276@90C
Shuttle Panel F -P1 +A276@80C
Shuttle Panel F P1A276@20C
Shuttle Panel G P2A276@50C
Llumalloy
Teflon
Epoxy coated Kevlar
S-383 Silicone Rubber, 75C
S-383 Preconditioned 25C
S-383 Preconditioned 50C
S-383 Preconditioned 75C
Teflon TE9302 at 25C
Teflon TE9302 at 50C
Teflon TE9302 at 77C
Scotch Weld 3501 at 25C
Scotch Weld 3501 at 50C
Scotch-Weld 3501at 75C
MLI Preconditioned 25C
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Appendix 2: Refractive and Absorptive Indices listing for thin solid films condensed from gases and material outgassing products

1) Ammonia (NH3) at 20K  
2) Ammonia (NH3) at 77K  
3) Argon at 20K  
4) Argon-H2O mixture at 20K  
5) Carbon Dioxide (CO2) at 77K  
6) Carbon Dioxide (CO2) at 20K  
7) Carbon Monoxide (CO) at 20K  
8) Carbon Monoxide-H2O mixture at 20K  
9) Water (H2O) at 20K  
10) Water (H2O) at 50K  
11) Water (H2O) at 77K  
12) H2O-CO2 mixture at 77K  
13) Hydrogen Chloride (HCL) at 20K  
14) Methane (CH4) at 20K  
15) N2-CO2 mixture at 20K  
16) N2-CO mixture at 20K  
17) N2-CO-CO2 mixture at 20K  
18) N2-H2O mixture at 20K  
19) N2-NH3 mixture at 20K  
20) Nitrogen (N2) at 20K  
21) Nitric Oxide (NO) at 20K  
22) Oxygen (O2) at 20K  
23) Bipropellant engine exhaust gases at 25K  
24) Bipropellant engine exhaust gases at 75K  
25) Hydrazine (N2H4) at 80K  
26) Monomethyl hydrazine (MMH) at 20K  
27) Monomethyl hydrazine (MMH) at 80K  
28) Nitrogen Tetroxide (N2O4) at 20K  
29) Nitrogen Tetroxide (N2O4) at 80K  
30) Simulated Bipropellant engine gases at 20K  
31) Chemglaze A276 Paint  
32) Chemglaze Z306 Paint  
33) Crest 74  
34) DC6-1104  
35) DC93-500  
36) EP30LI Composite  
37) J2AS4 Composite  
38) Kapton
39) Lockheed-100 Paint
40) Lockheed-200 Paint
41) Lockheed-300 Paint
42) Mylar
43) NVF
44) Polyclad
45) RTV-560
46) RTV-566
47) RTV-732
48) Torrseal
49) Uralane 5753
50) Vackote Oil
SOFTWARE USAGE AGREEMENT (SUA)

Satellite Contamination and Materials Outgassing Knowledgebase
“…An exhaustive database reference…”

Export Classification of CCL ECCN EAR 9D001

Please note: The signature of this SUA must be a US Citizen and may be responsible for any export control issues that may arise from this technology transfer.

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Name: Satellite Contamination and Materials Outgassing Knowledgebase Version 2.0

Version: 2.0 NASA Case No: 32183-1 (hereinafter SOFTWARE).

The authority for NASA to release SOFTWARE is NASA Policy Directive (NPD) 2210.1.

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Executed on Behalf of RECIPIENT by:

_____________________________  _____________________
Caroline K. Wang               Date
Software Release Authority

_____________________________  _____________________
Recipient Signature            Date

_____________________________
Recipient Name (printed)

_____________________________
Title

(Indicate formal title if signing as an authorized representative of a company or entity.
If signing as an individual, fill in the Title line as “Individual”)
Space Environmental Effects Knowledgebase

B.E. Wood

Bob Wood Aerospace Consulting Services, Inc. (BWACS)
402 Lannom Circle
Tullahoma, TN 37388-2464

National Aeronautics and Space Administration
Washington, DC 20546–0001

Prepared for Technical Monitor: Dr. Dale Ferguson

This report describes the results of an NRA funded program entitled “Space Environmental Effects Knowledgebase” that received funding through a NASA NRA (NRA8-31) and was monitored by personnel in the NASA Space Environmental Effects (SEE) Program. The NASA Project number was 02029. The Satellite Contamination and Materials Outgassing Knowledgebase (SCMOK) was created as a part of the earlier NRA8-20. One of the previous tasks and part of the previously developed Knowledgebase was to accumulate data from facilities using QCMs to measure the outgassing data for satellite materials. The main object of this current program was to increase the number of material outgassing datasets from 250 up to ~500. As a part of this effort, a round-robin series of materials outgassing measurements program was also executed that allowed comparison of the results for the same materials tested in 10 different test facilities. Other programs tasks included obtaining datasets or information packages for 1) optical effects of contaminants on optical surfaces, thermal radiators, and sensor systems and 2) space environmental effects data and incorporating these data into the already existing NASA/SEE Knowledgebase.
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